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Olympus LCPLN50XIR 50X NIR Objective

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Olympus LCPLN50XIR 50X NIR Objective

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€8.100⁰⁰

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General

LCPLN50XIR **Model Number:**

Compatible Tube Lens Focal Length (mm):
Focal Length: 180mm

Microscope Objective **Type:**

Infinity Corrected **Style:**

Olympus **Manufacturer:**

Physical & Mechanical Properties

0.44 **Field of View (mm):**

40.50 **Length excluding Threads (mm):**

31.00 **Maximum Diameter (mm):**

169 **Weight (g):**

Optical Properties

Compatible Cover Glass Thickness (mm):
Glass: 0 - 1.2mm
Silicon: 0 - 1.2mm

3.60 **Focal Length FL (mm):**

50X **Magnification:**

0.65 **Numerical Aperture NA:**

0.52 **Resolving Power (μm):**

0.65 **Depth of Field (μm):**

Working Distance (mm):
Glass: 4.50 - 3.76mm
Silicon: 4.50 - 4.20mm

400 - 1600 **Wavelength Range (nm):**

22 **Field Number (mm):**

45 **Parfocal Length (mm):**

N/A **Immersion Liquid:**

4.68 **Entrance Pupil Diameter (mm):**

Threading & Mounting

RMS / 20.32mm x 36 TPI **Mounting Threads:**

Regulatory Compliance

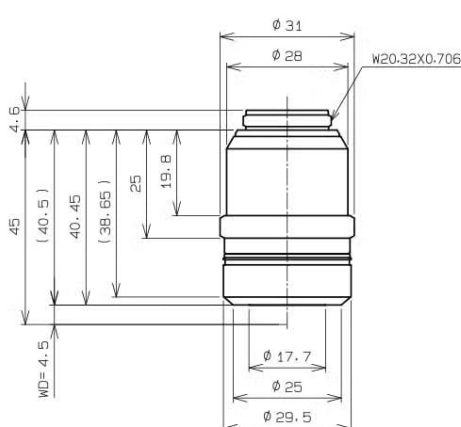
[View](#) **Certificate of Conformance:**

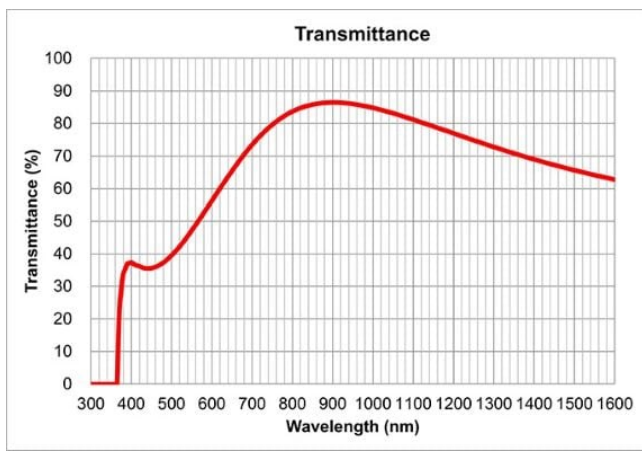
Product Details

- Long Working Distances to Reduce Risk of Specimen Damage
- Correction Collars to Adjust for Specimen Thickness
- Ideal for Silicon Wafer Inspection

Olympus Plan Achromatic Near-Infrared Objectives provide high transmission between 700 - 1600nm, making them an excellent choice for near-infrared microscopy when coupled with an NIR tube lens. These objectives feature long working distances to reduce the risk of damage to specimens and support up to field number 22 for observation. Magnifications of 20X and higher feature a correction collar to correct for aberrations based on the thickness of either the glass or silicon substrate being inspected. Olympus Plan Achromatic Near-Infrared Objectives are ideal for use in silicon wafer inspection to view the internal structure for defects.

Technical Information





LCPLN50XIR Transmission Graph

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